

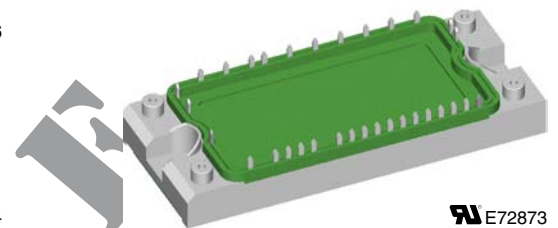
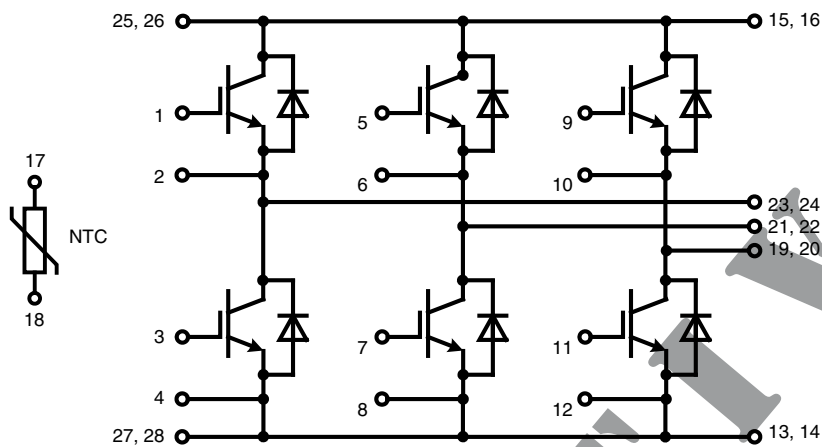
Six-Pack

Trench XPT IGBT

$V_{CES} = 650\text{ V}$
 $I_{C25} = 71\text{ A}$
 $V_{CE(sat) \text{ typ.}} = 1.55\text{ V}$

Part name (Marking on product)

MIXD50W650TED



E72873

Pin configuration see outlines.

Features:

- Easy paralleling due to the positive temperature coefficient of the on-state voltage
- Rugged XPT design (Xtreme light Punch Through) results in:
 - short circuit rated for 10 μsec .
 - very low gate charge
 - square RBSOA @ $3 \times I_C$
 - low EMI
- Thin wafer technology combined with the XPT design results in a competitive low $V_{CE(sat)}$
- SONIC™ diode
 - fast and soft reverse recovery
 - low operating forward voltage

Application:

- AC motor drives
- Solar inverter
- Medical equipment
- Uninterruptible power supply
- Air-conditioning systems
- Welding equipment
- Switched-mode and resonant-mode power supplies

Package:

- "E2-Pack" standard outline
- Insulated copper base plate
- Soldering pins for PCB mounting
- Temperature sense included

IGBTs

Symbol	Definitions	Conditions	Ratings			Unit
			min.	typ.	max.	
V_{CES}	collector emitter voltage	$T_{VJ} = 25^{\circ}\text{C}$			650	V
V_{GES}	max. DC gate voltage	continuous			± 20	V
V_{GEM}	max. transient collector gate voltage	transient			± 30	V
I_{C25}	collector current	$T_{VJ} = 175^{\circ}\text{C}$	$T_C = 25^{\circ}\text{C}$		71	A
I_{C80}			$T_C = 80^{\circ}\text{C}$		54	A
P_{tot}	total power dissipation	$T_C = 25^{\circ}\text{C}$			190	W
$V_{CE(sat)}$	collector emitter saturation voltage	$I_C = 50\text{ A}; V_{GE} = 15\text{ V}$ (on die level)	$T_{VJ} = 25^{\circ}\text{C}$ $T_{VJ} = 150^{\circ}\text{C}$	1.55 1.85	1.80	V V
$V_{GE(th)}$	gate emitter threshold voltage	$I_C = 0.8\text{ mA}; V_{GE} = V_{CE}$	$T_{VJ} = 25^{\circ}\text{C}$	5.0	6.5	V
I_{CES}	collector emitter leakage current	$V_{CE} = V_{CES}; V_{GE} = 0\text{ V}$	$T_{VJ} = 25^{\circ}\text{C}$ $T_{VJ} = 150^{\circ}\text{C}$	20 0.60	200	μA mA
I_{GES}	gate emitter leakage current	$V_{CE} = 0\text{ V}; V_{GE} = \pm 20\text{ V}$			500	nA
C_{ies}	input capacitance	$V_{CE} = 25\text{ V}; V_{GE} = 0\text{ V}; f = 1\text{ MHz}$		tbd		nF
$Q_{G(on)}$	total gate charge	$V_{CE} = 300\text{ V}; V_{GE} = 0...15\text{ V}; I_C = 50\text{ A}$			130	nC
$t_{d(on)}$	turn-on delay time	inductive load $V_{CE} = 300\text{ V}; I_C = 50\text{ A}$ $V_{GE} = \pm 15\text{ V}; R_G = 15\ \Omega$	$T_{VJ} = 150^{\circ}\text{C}$		25	ns
t_r	current rise time				45	ns
$t_{d(off)}$	turn-off delay time				120	ns
t_f	current fall time				40	ns
E_{on}	turn-on energy per pulse				0.80	mJ
E_{off}	turn-off energy per pulse				1.20	mJ
$E_{rec(off)}$	reverse recovery losses at turn-off				tbd	mJ
I_{CM}	reverse bias safe operating area	RBSOA; $V_{GE} = \pm 15\text{ V}; R_G = 15\ \Omega; L = 100\ \mu\text{H}$ clamped inductive load;	$T_{VJ} = 150^{\circ}\text{C}$		100	A
V_{CEK}					650	V
t_{sc} (SCSOA)	short circuit safe operating area	$V_{CE} = 360\text{ V}; V_{GE} = \pm 15\text{ V};$ $R_G = 15\ \Omega;$ non-repetitive	$T_{VJ} = 150^{\circ}\text{C}$		10	μs A
R_{thJC}	thermal resistance junction to case	(per IGBT)			0.80	K/W
R_{thCH}	thermal resistance case to heatsink	(per IGBT)			0.30	K/W

Diodes

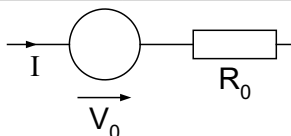
Symbol	Definitions	Conditions	Maximum Ratings		
			min.	max.	
V_{RRM}	max. repetitive reverse voltage			650	V
I_{F25}	forward current	$T_{VJ} = 175^{\circ}\text{C}$	$T_C = 25^{\circ}\text{C}$	55	A
I_{F80}			$T_C = 80^{\circ}\text{C}$	40	A

Symbol	Conditions	Characteristic Values				
		min.	typ.	max.		
V_F	forward voltage	$I_F = 50\text{ A}$	$T_{VJ} = 25^{\circ}\text{C}$ $T_{VJ} = 150^{\circ}\text{C}$	1.7 1.9	2.0	V V
Q_{RR}	reverse recovery charge	$V_R = 325\text{ V}; I_F = 50\text{ A}$ $di_F/dt = -900\text{ A}/\mu\text{s}$	$T_{VJ} = 150^{\circ}\text{C}$		4.5	μC
I_{RM}	max. reverse recovery current				45	A
t_{rr}	reverse recovery time				150	ns
$E_{rec(off)}$	reverse recovery losses at turn-off				1.0	mJ
R_{thJC}	thermal resistance junction to case	(per diode)			1.2	K/W
R_{thCH}	thermal resistance case to heatsink	(per diode)			0.4	K/W

Module

Symbol	Definitions	Conditions	Ratings			Unit
			min.	typ.	max.	
T_{VJ}	operating temperature		-40		150	°C
T_{VJM}	max. virtual junction temperature				175	°C
T_{stg}	storage temperature		-40		125	°C
V_{ISOL}	isolation voltage	$I_{ISOL} \leq 1 \text{ mA}; 50/60 \text{ Hz}$	1 min. 1 sec.		2500 3000	V~ V~
M_d	mounting torque	(M4)	2.0		2.2	Nm
d_s	creep distance on surface		11.5			mm
d_A	strike distance through air		10.0			mm
Weight				40		g
$R_{pin-chip}$	resistance pin to chip	$V = V_{CEsat} + 2 \cdot R \cdot I_C$ resp. $V = V_F + 2 \cdot R \cdot I_F$		6		mΩ

Equivalent Circuits for Simulation

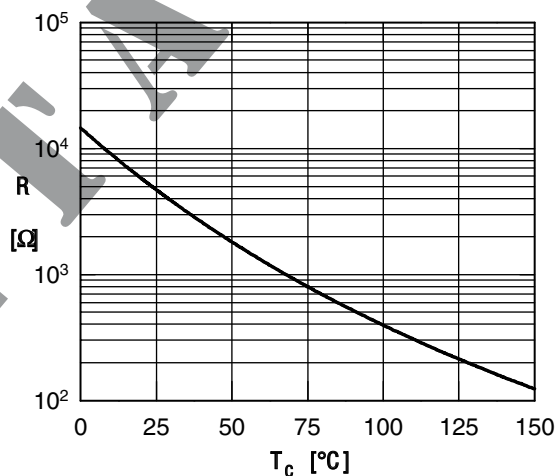


Ratings

Symbol	Definitions	Conditions	min.	typ.	max.	Unit
V_0	IGBT	$T_{VJ} = 175^\circ\text{C}$		0.8		V
R_0				26		mΩ
V_0	Diode	$T_{VJ} = 175^\circ\text{C}$		1.15		V
R_0				18		mΩ

Temperature Sensor NTC

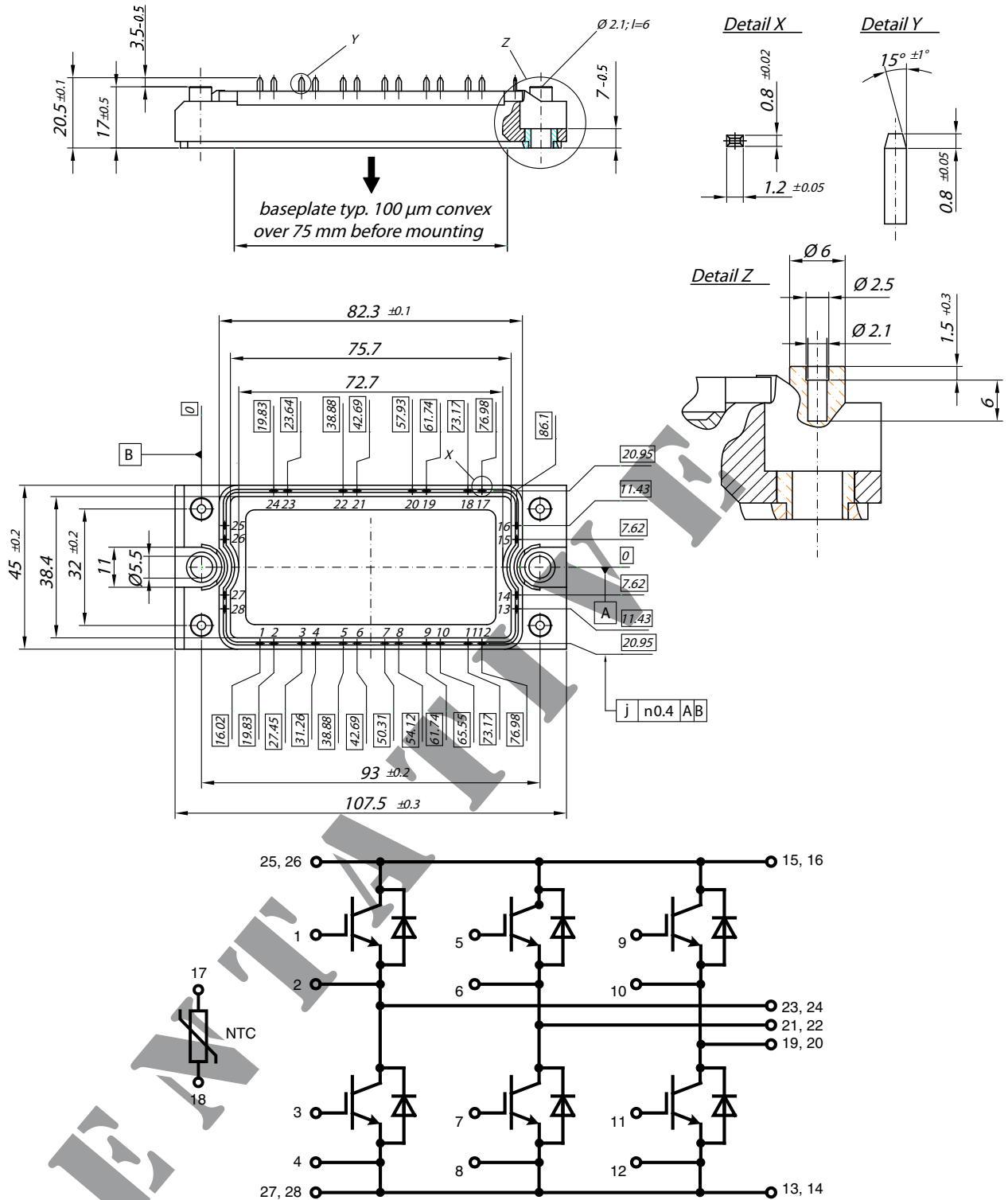
Symbol	Definitions	Conditions	Ratings			Unit
			min.	typ.	max.	
R_{25}	resistance	$T_c = 25^\circ\text{C}$	4.75	5.0	5.25	kΩ
$B_{25/50}$				3375		K



Typ. NTC resistance vs. temperature

Outline Drawing

Dimensions in mm (1 mm = 0.0394")



Product Marking

Ordering	Part Name	Marking on Product	Delivering Mode	Base Qty	Ordering Code
Standard	MIXD50W650TED	MIXD50W650TED	Box	6	tbd